

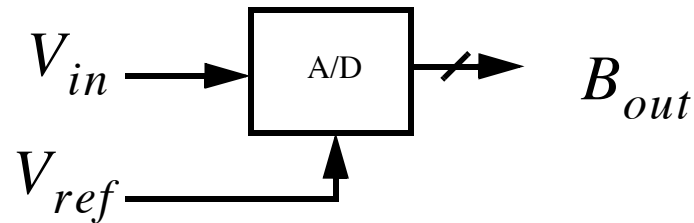
Nyquist-Rate A/D Converters

**Reference: Chapter 13 of the text
“Analog Integrated Circuit Design”
by
David Johns and Ken Martin**

Chapter 17 of the 2nd Edition of the text by Tony Chan Carusone, David Johns, and Ken Martin

The material of this presentation is courtesy of Dr. Ken Martin.

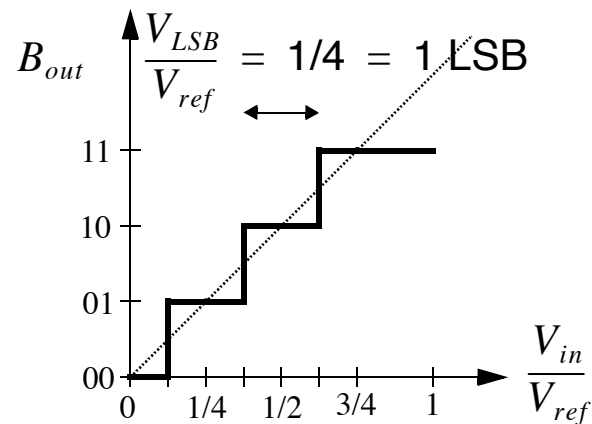
A/D Converter Basics



$$V_{ref}(b_1 2^{-1} + b_2 2^{-2} + \dots + b_N 2^{-N}) = V_{in} \pm x$$

$$\text{where } \left(-\frac{1}{2} V_{LSB} < x < \frac{1}{2} V_{LSB} \right) \quad (1)$$

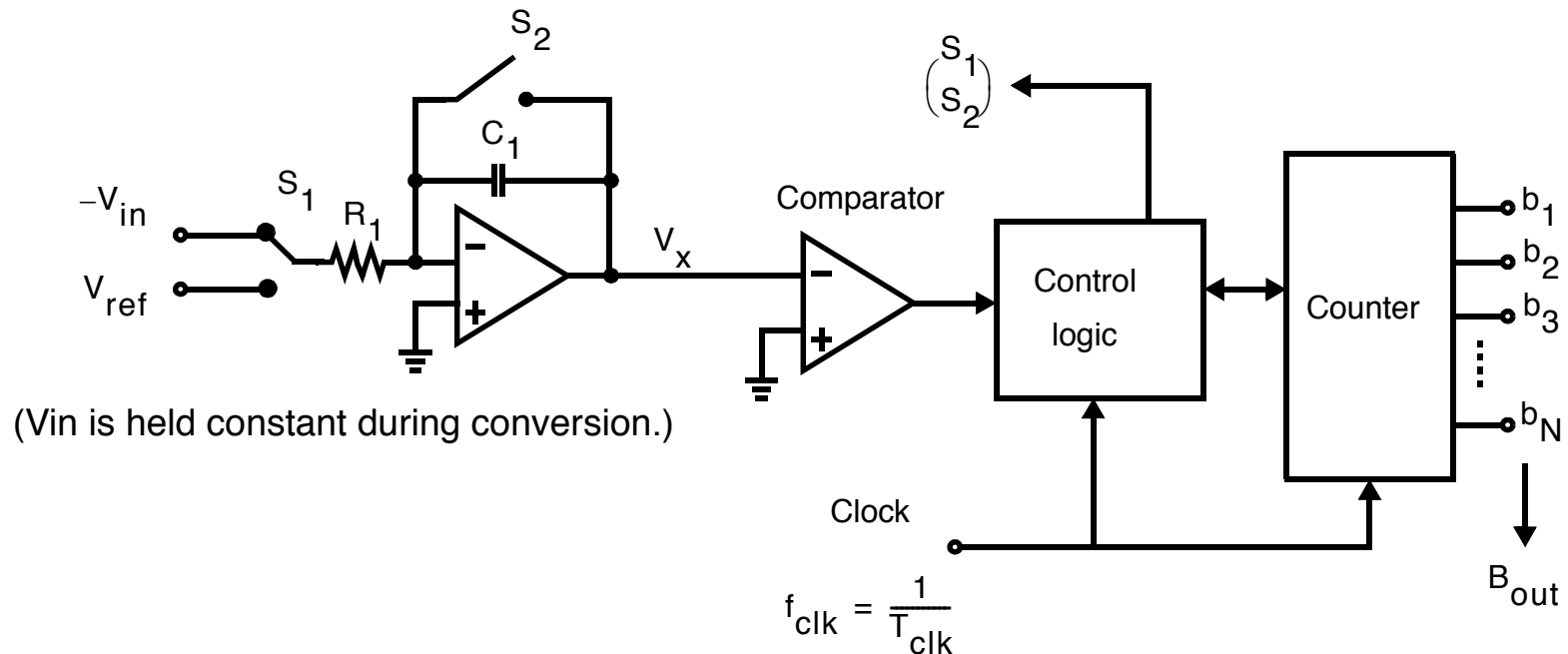
- A range of valid input values produce the same output signal — quantization error.



Analog to Digital Converters

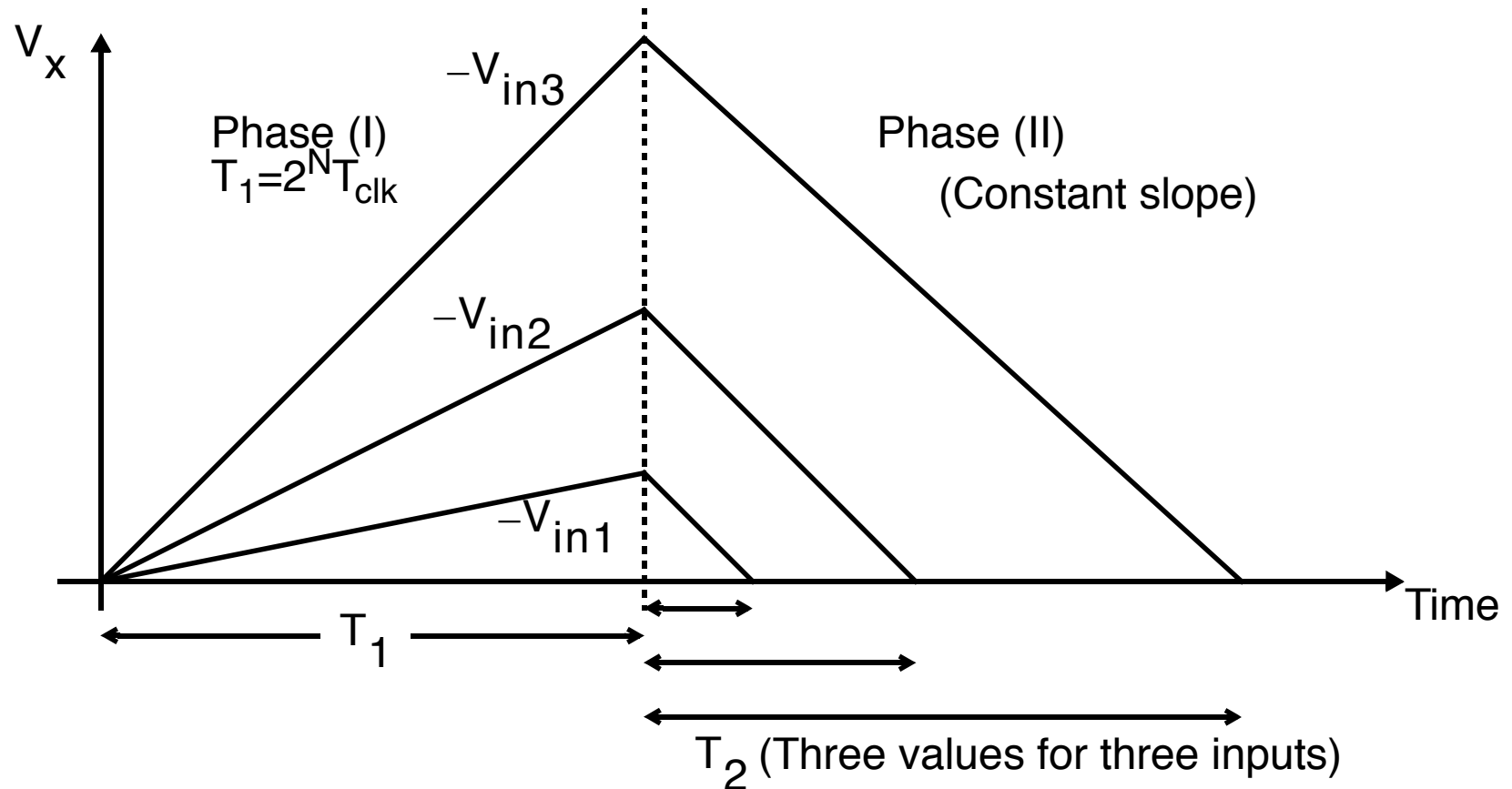
Low to Medium Speed, High Accuracy	Medium Speed, Medium Accuracy	High Speed, Low to Medium Accuracy
Integrating	Successive approximation	Flash
Oversampling (not Nyquist-rate)	Algorithmic	Two-step
		Interpolating
		Folding
		Pipelined
		Time-interleaved

Integrating Converters



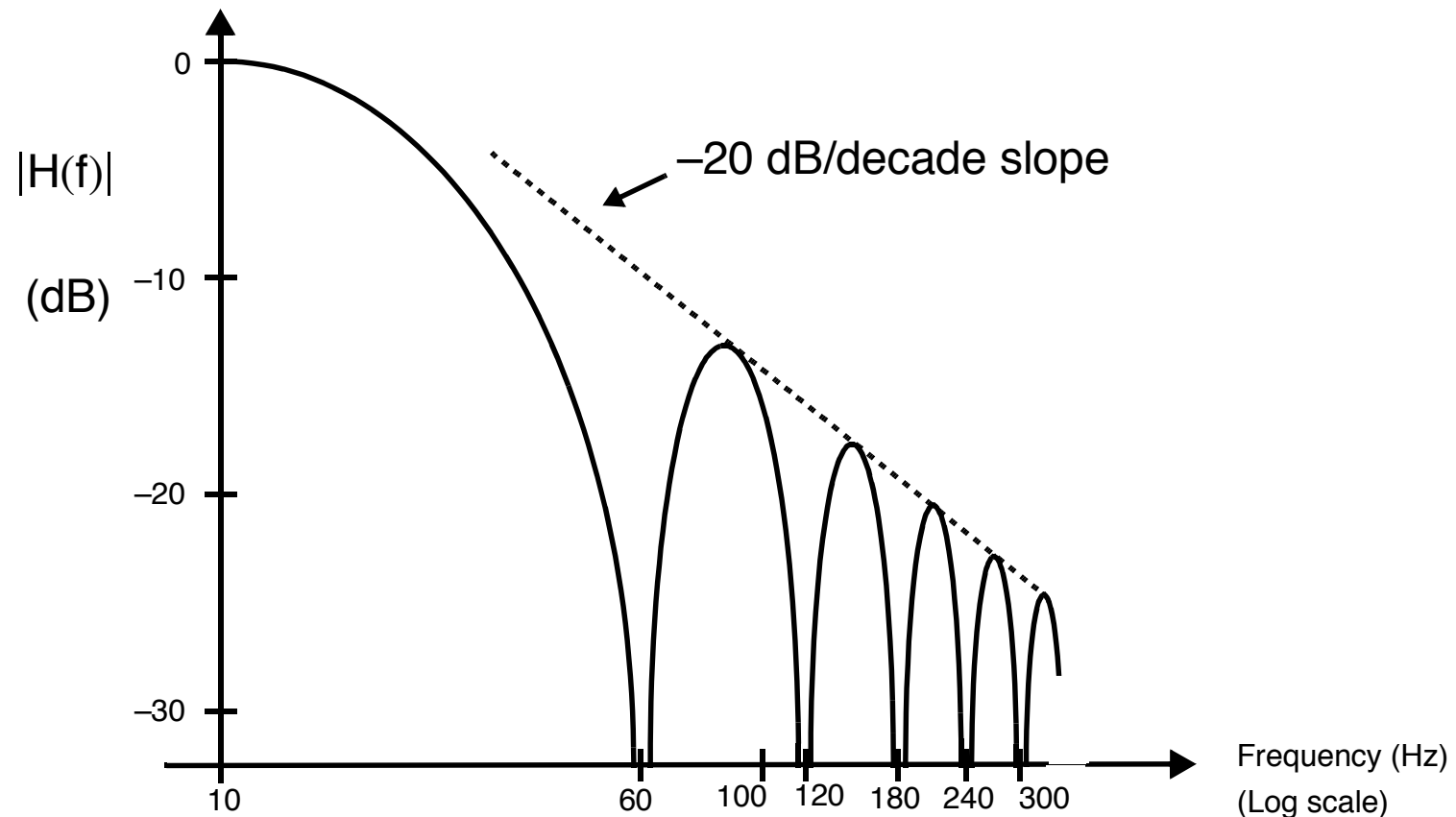
- Low offset and gain errors for low-speed applications
- Small amount of circuitry
- Worst case conversion speed is $f_{clk}/2^{N+1}$

Integrating Converters



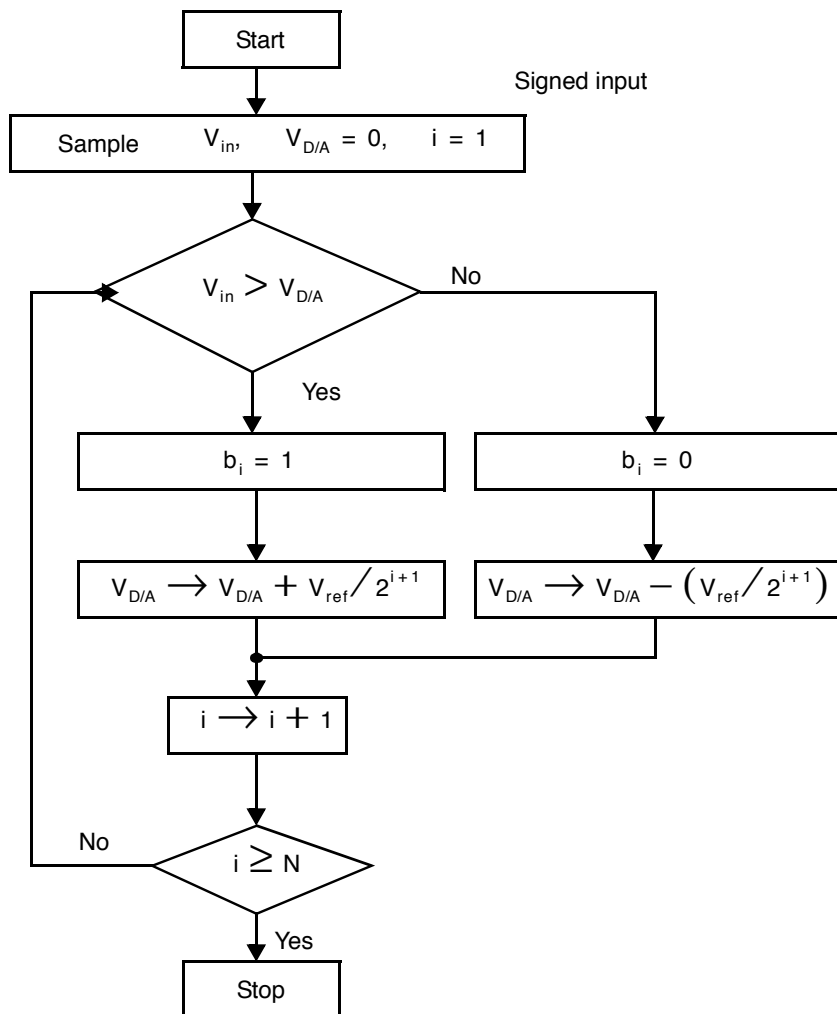
- Count at end of T_2 is digital output
- Does not depend on RC time-constant

Integrating Converters



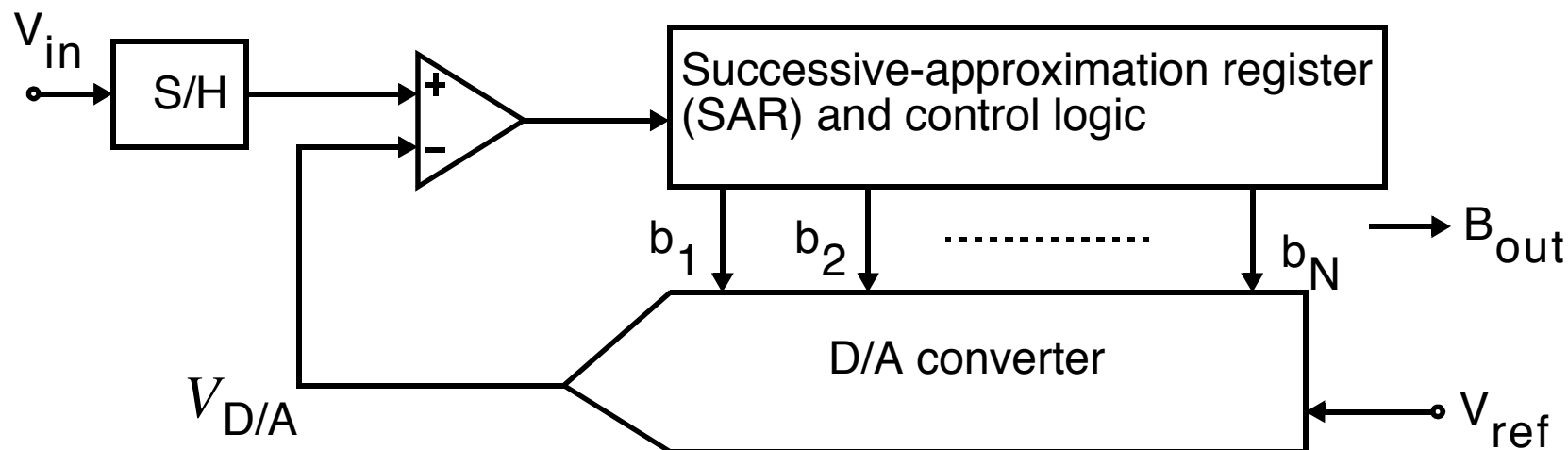
- Notches the input frequencies which are multiples of $1/T_1$

Successive-Approximation Converters



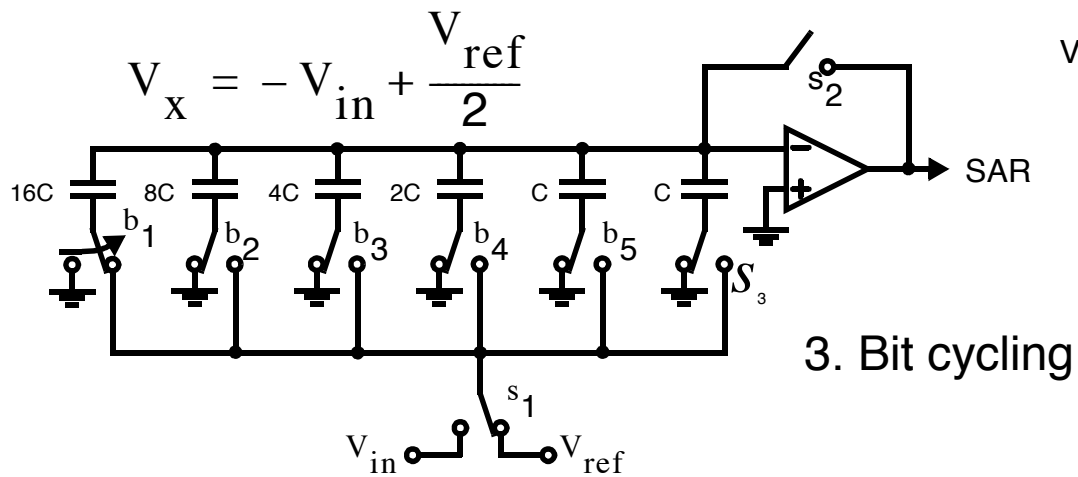
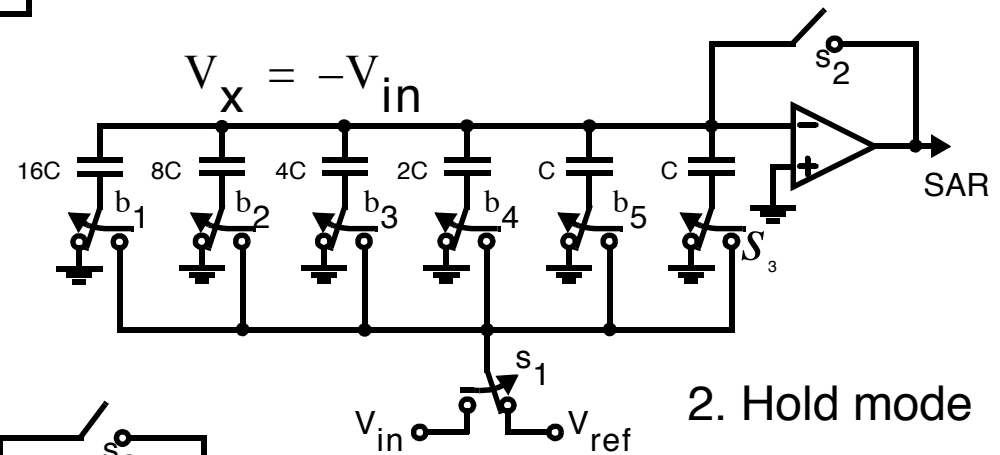
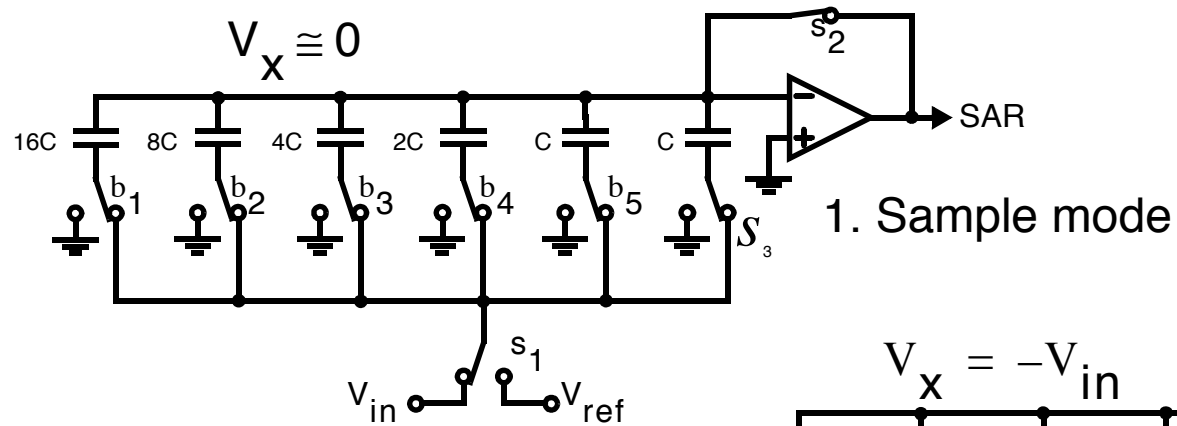
- Makes use of binary search algorithm
- Requires N steps for N-bit converter
- Successively “tunes” a signal until within 1 LSB of input
- Medium speed
- Moderate accuracy

DAC Based Successive-Approximation



- Adjust $V_{D/A}$ until within 1 LSB of V_{in}
- Start with MSB and continue until LSB found
- D/A mainly determines overall accuracy
- Input S/H required

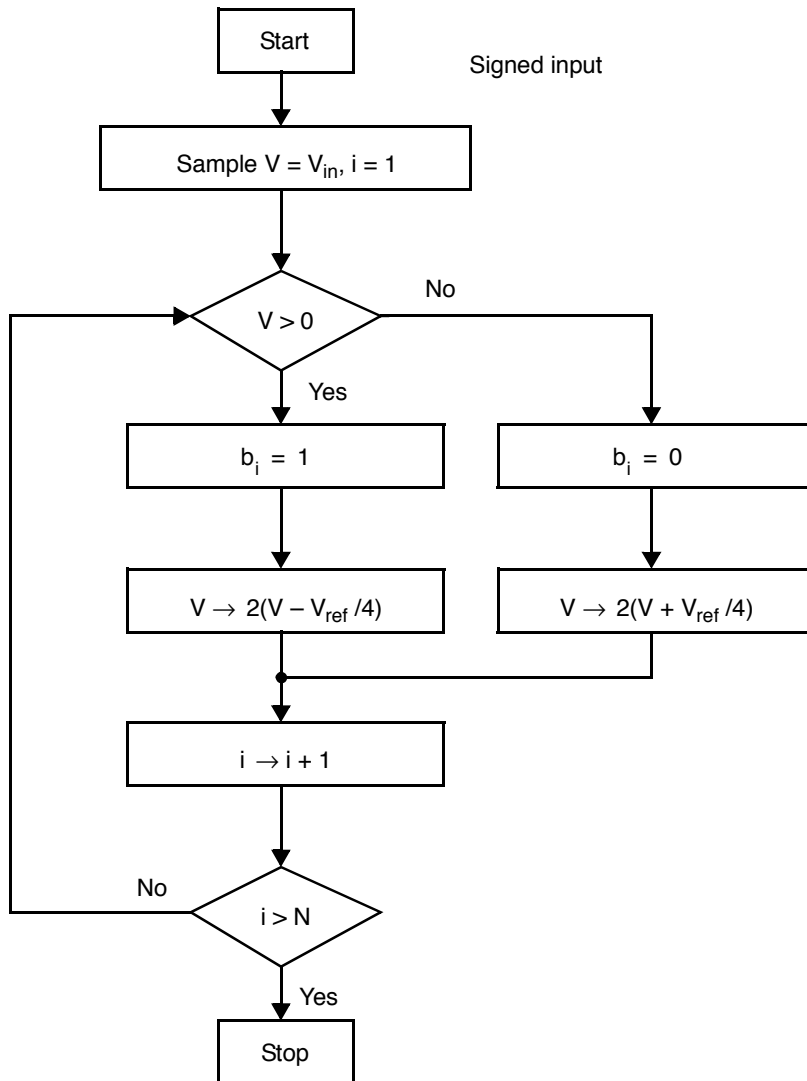
Charge Redistribution A/D



Charge Redistribution A/D

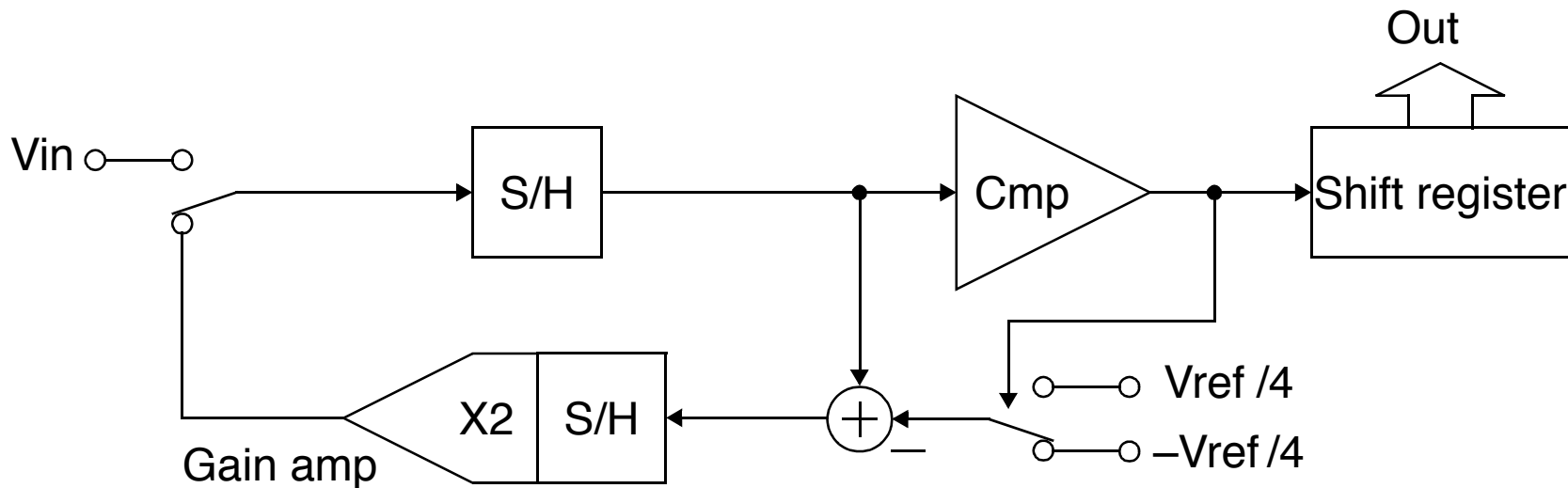
- McCreary, 75
- Combines S/H, D/A converter, and difference circuit
- *Sample mode*: Caps charged to V_{in} , comparator reset.
- *Hold mode*: Caps switched to gnd so $V_x = -V_{in}$
- *Bit cycling*: Cap switched to V_{ref} . If $V_x < 0$ cap left connected to V_{ref} and bit=1. Otherwise, cap back to gnd and bit=0. Repeat N times
- Cap *bottom plates* connected to V_{ref} side to minimize parasitic capacitance at V_x . Parasitic cap does not cause conversion errors but it attenuates V_x .

Algorithmic (or Cyclic) A/D Converter



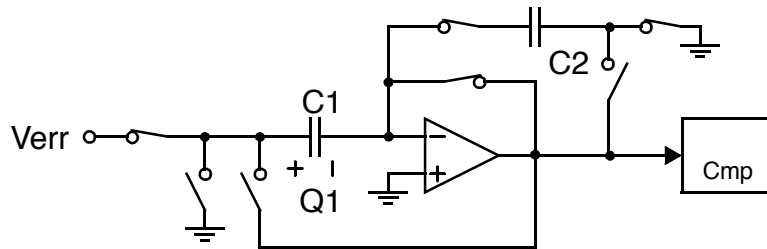
- Operates similar to successive-approx converter
- Successive-approx halves ref voltage each cycle
- Algorithmic doubles error each cycle (leaving ref voltage unchanged)

Algorithmic Converter

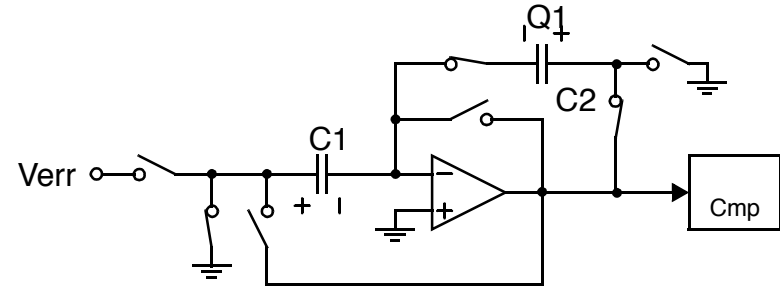


- McCharles, 77; Li, 84
- Small amount of circuitry — reuse cyclically in time
- Requires a high-precision multiply by 2 gain stage

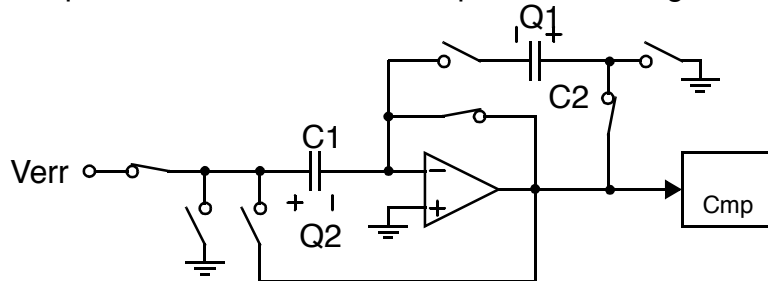
Ratio-Independent Multiply-by-Two



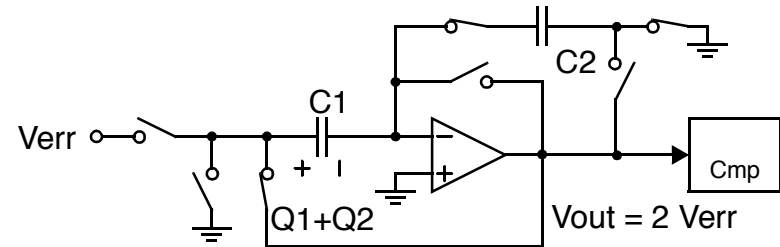
1. Sample remainder and cancel input-offset voltage.



2. Transfer charge Q_1 from C_1 to C_2 .



3. Sample input signal with C_1 again after storing charge Q_1 on C_2 .

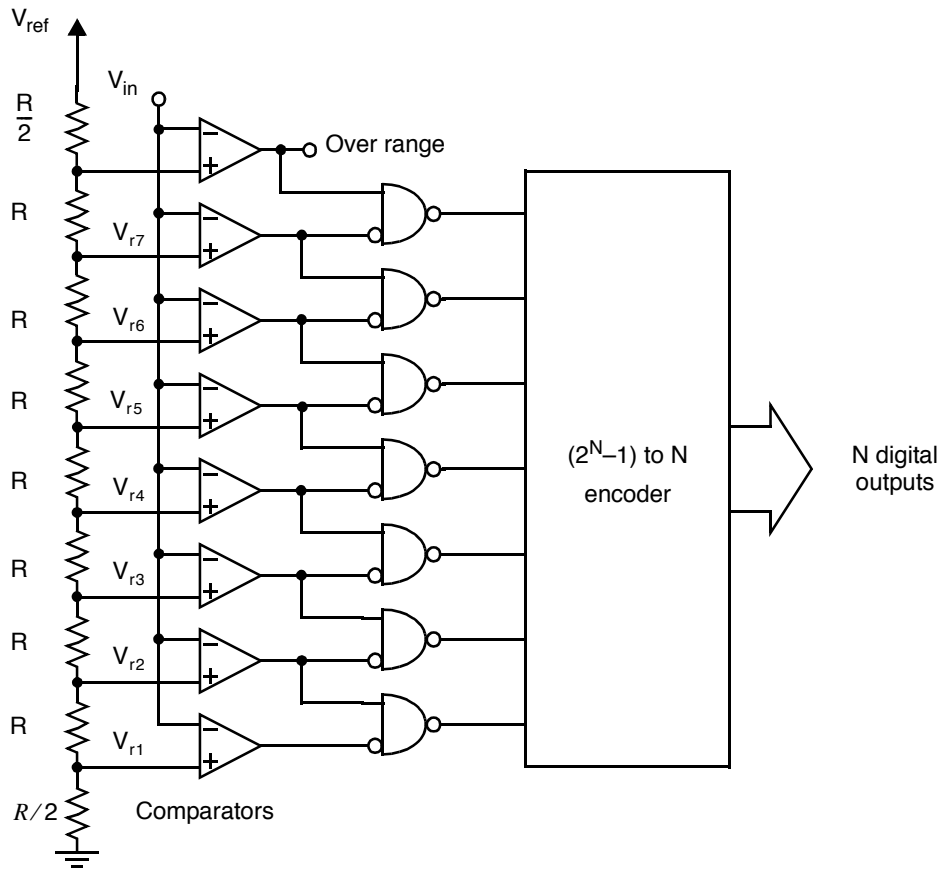


4. Combine Q_1 and Q_2 on C_1 , and connect C_1 to output.

- Does not rely on cap matching
- Sample input twice using C_1 ; hold first charge in C_2 and re-combine with first charge on C_1

Flash (or Parallel) Converters

- Peetz, 86; Yoshii, 87; Hotta, 87; and Gendai, 91



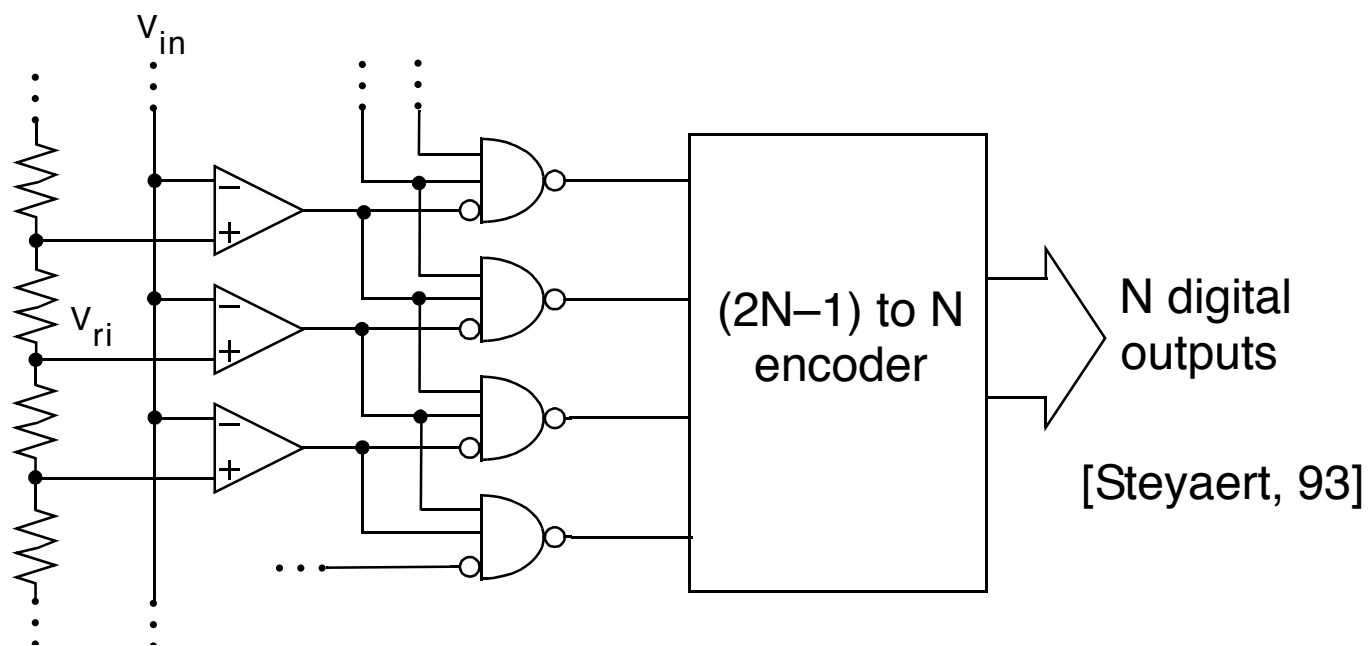
- High-speed
- Large size and typically power hungry
- 2^N comparators
- Speed bottleneck is usually the large capacitive load at input
- Thermometer code out of comps
- Nands used for simpler decoding and/or bubble error correction
- Use comp offset cancellation

Issues in Designing Flash A/D Converters

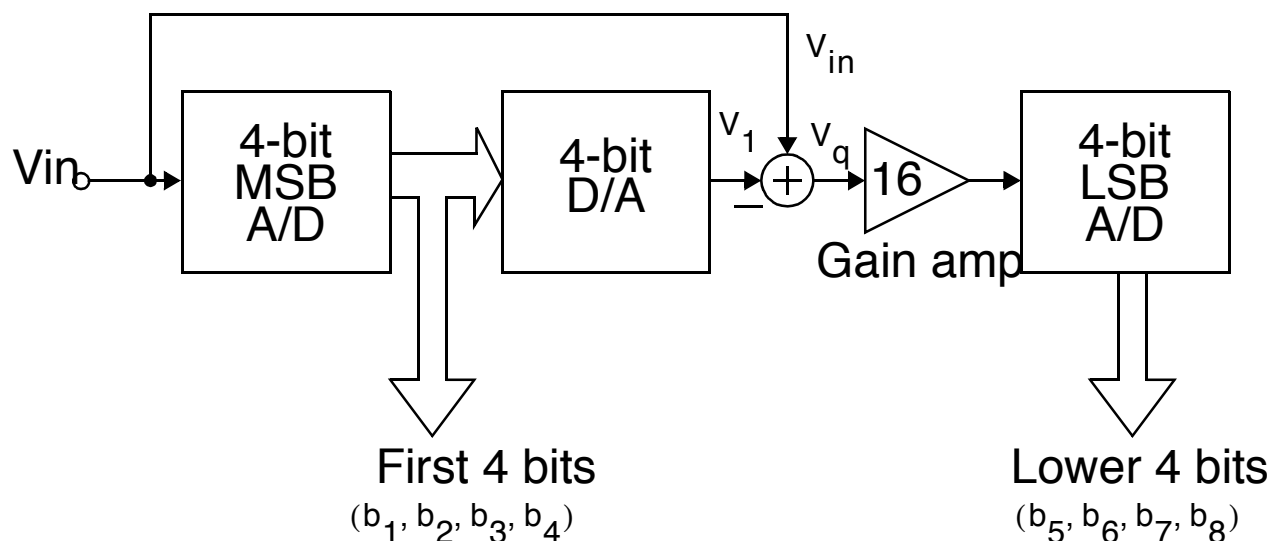
- ***Input Capacitive Loading*** — use interpolating arch.
- ***Signal and/or Clock Delay*** — Small arrival diff in clock or input cause errors. — route clock and V_{in} together with matched delays [Gendai, 1991]. Match capacitive loads
- ***Substrate and Power-Supply Noise*** — $V_{ref} = 2 V$ and 8-bit, 7.8 mV of noise causes 1 LSB error — shield clocks, use differential clocks, separate analog and digital supply, use on-chip supply cap bypass
- ***Flashback (Kickback)*** — Glitch at input due to going from track to latch mode — use preamplifiers in comparators and match input impedances
- ***Resistor-String Bowing*** — Due to I_{in} of bipolar comps — force center tap (or more) to be correct.

Flash Converters – Bubble Errors

- Thermometer code should be 111110000
- Bubble error (noise, metastability)— 111110100
- Usually occurs near transition point

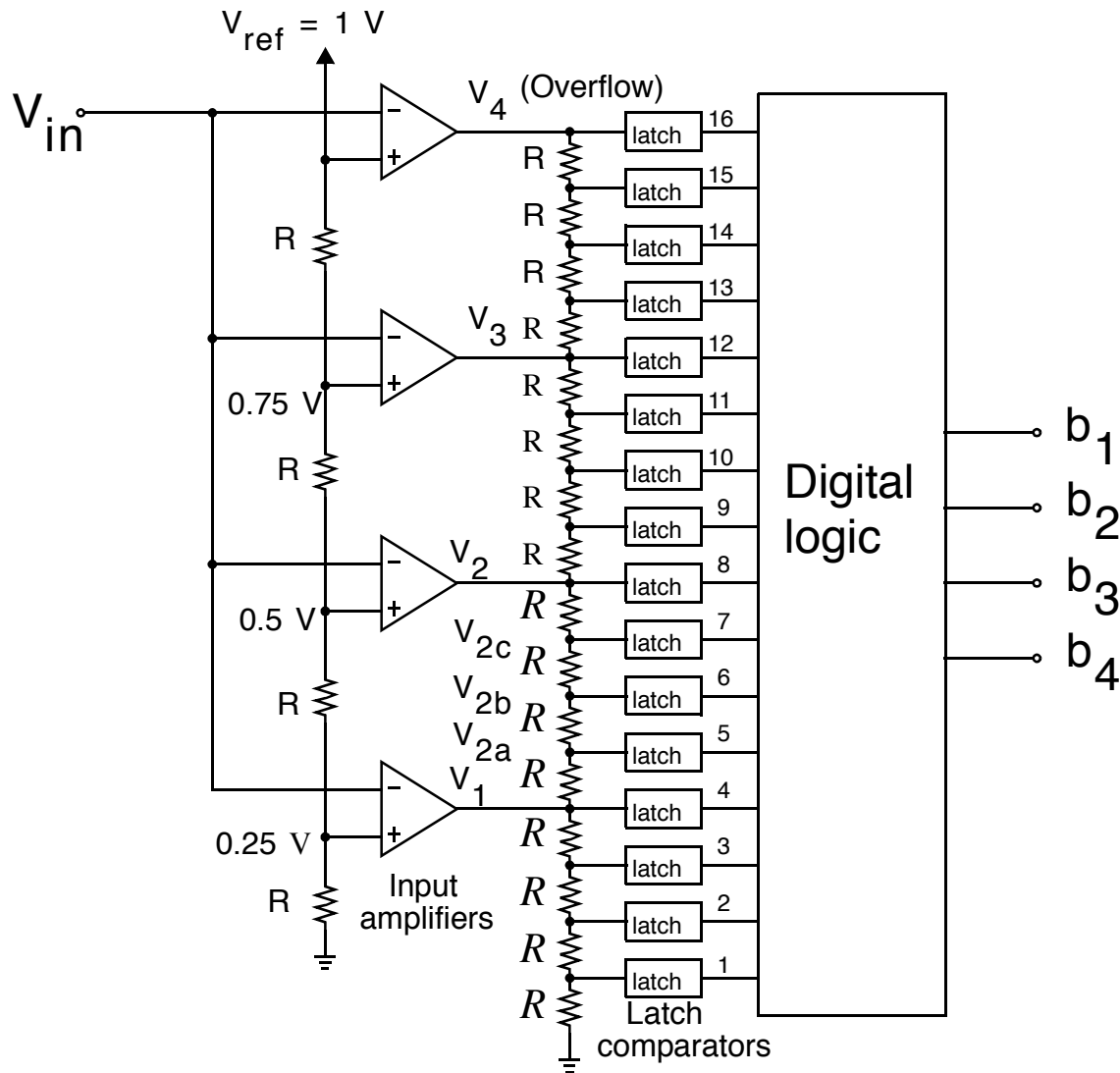


Two-Step A/D Converters



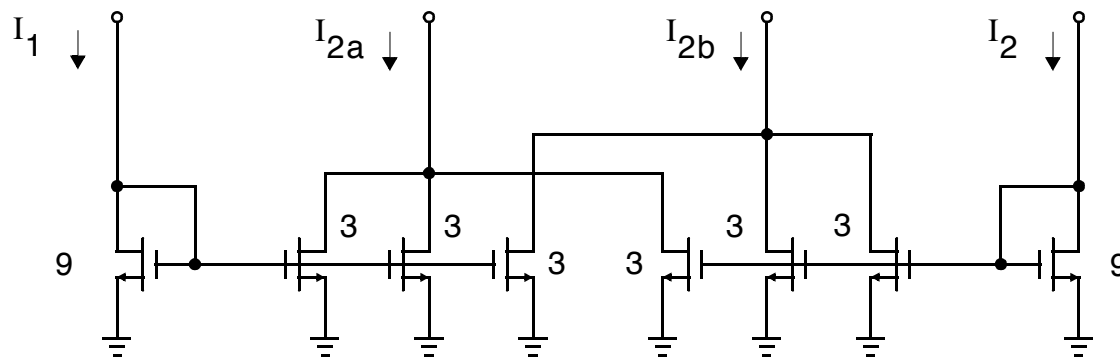
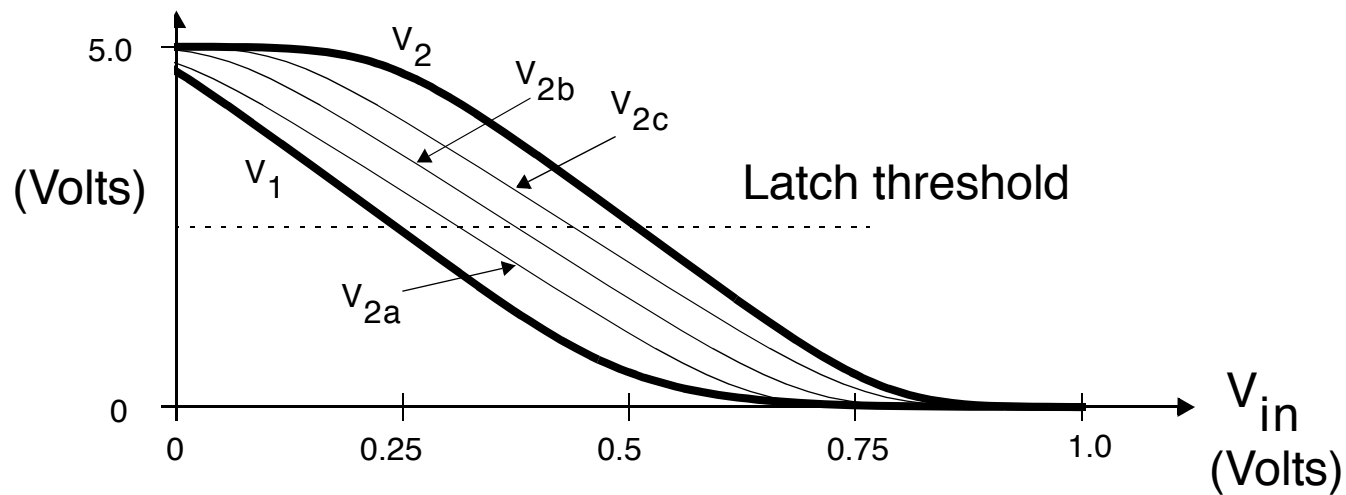
- High-speed, medium accuracy (but 1 sample latency)
- Less area, power, and capacitive loading than flash
- 32 comparators for 8-bit two-step (256 for flash)
- Gain amp likely sets speed limit
- Without digital error correction, many blocks need at least 8-bit accuracy

Interpolating A/D Converters



- Goodenough, 1989
- Steyaert, 1993
- Kusumoto, 1993
- Use input amps to amplify input around reference voltages
- Less cap on input (faster than flash)
- Match delays to latches
- Often combined with folding architecture

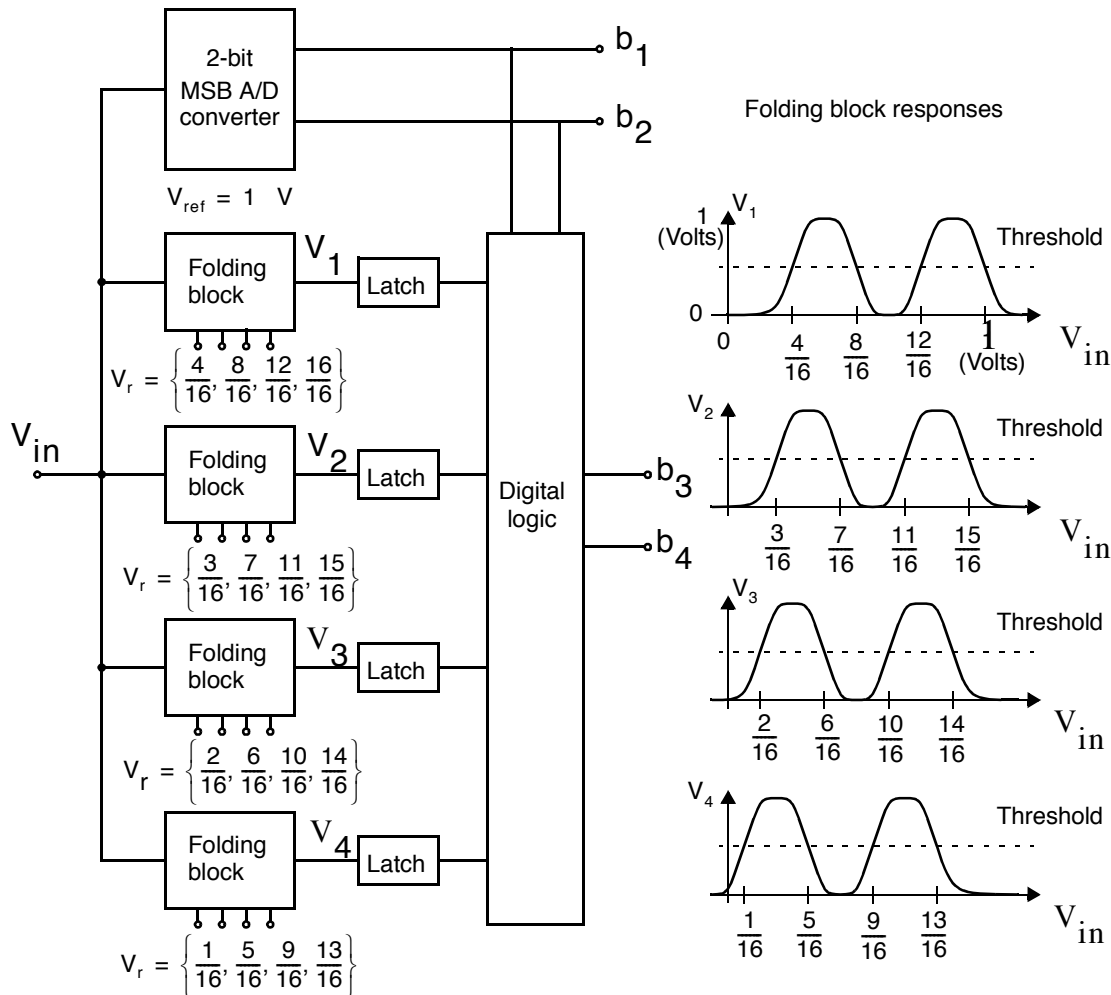
Interpolating Converters



(Relative width sizing shown)
(All lengths same)

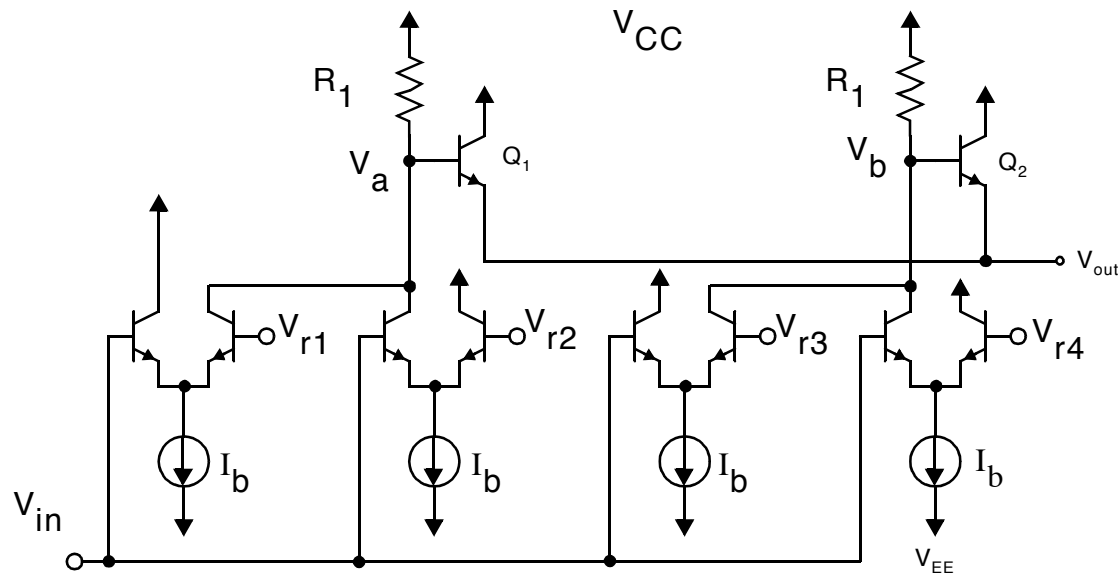
current interpolation

Folding A/D Converters

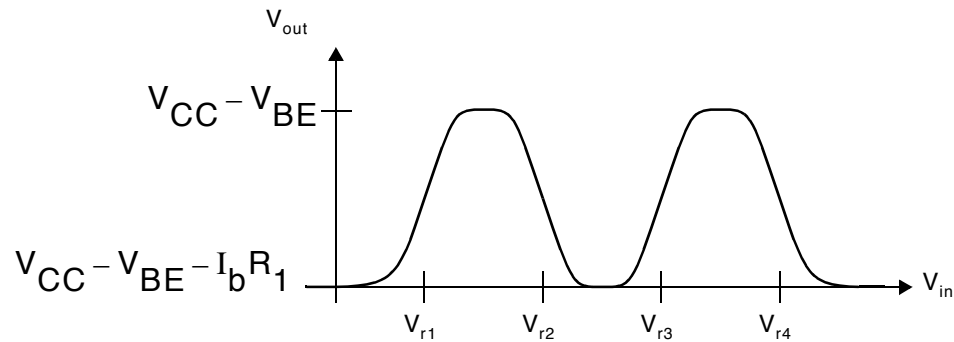


- Reduce number of latches using folding
- Save power and area
- Similar concept as 2-step
- Folding rate of 4 shown for 4 bit converter

Folding Circuit

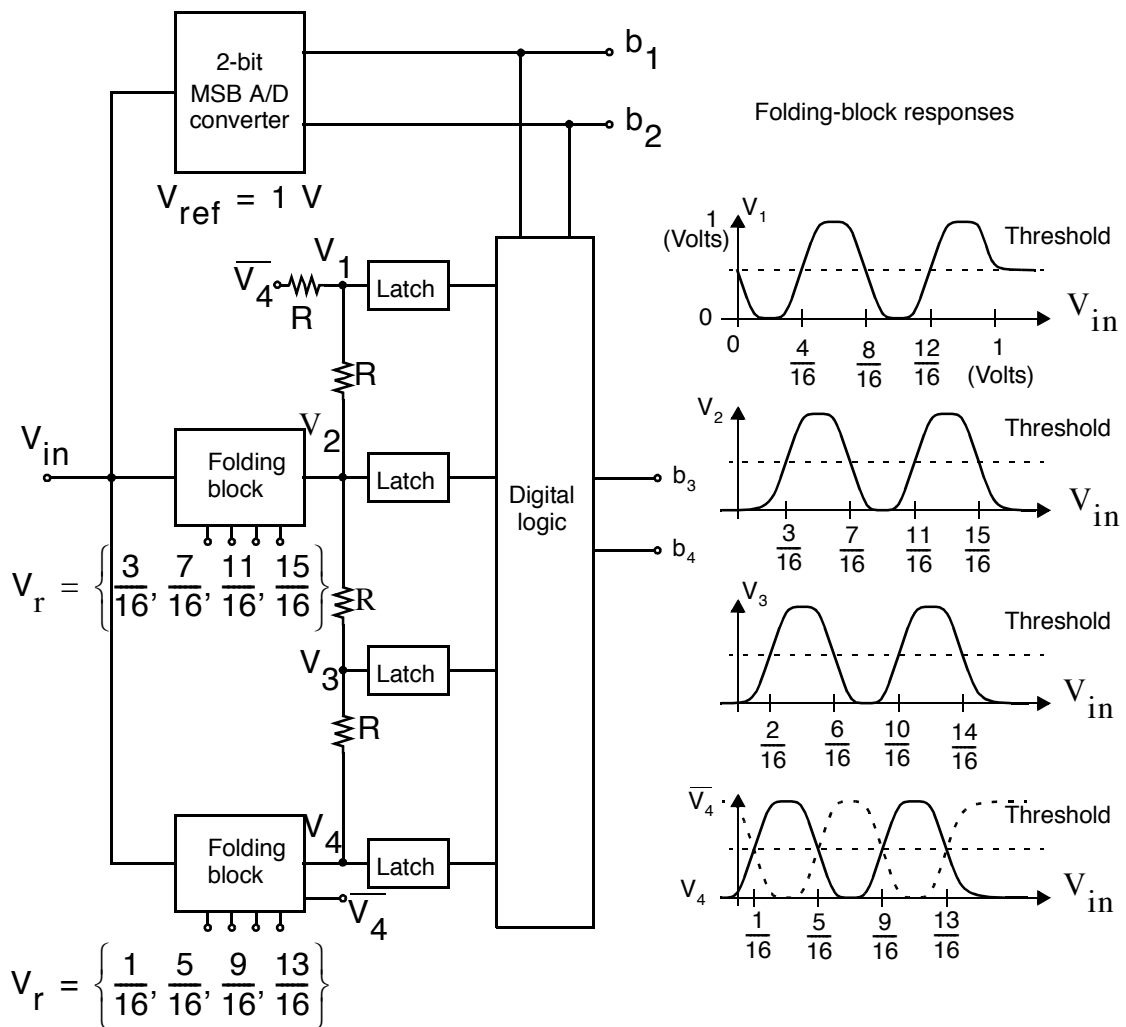


(a)



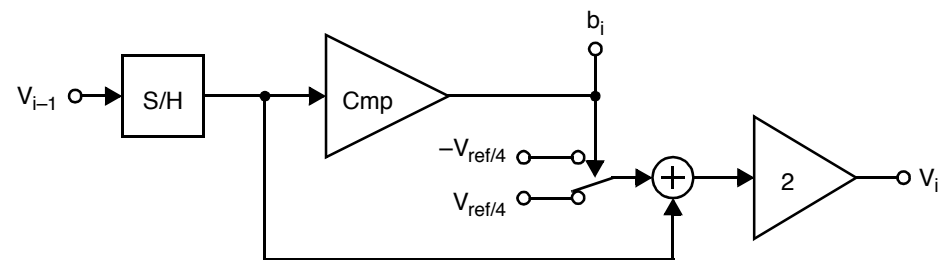
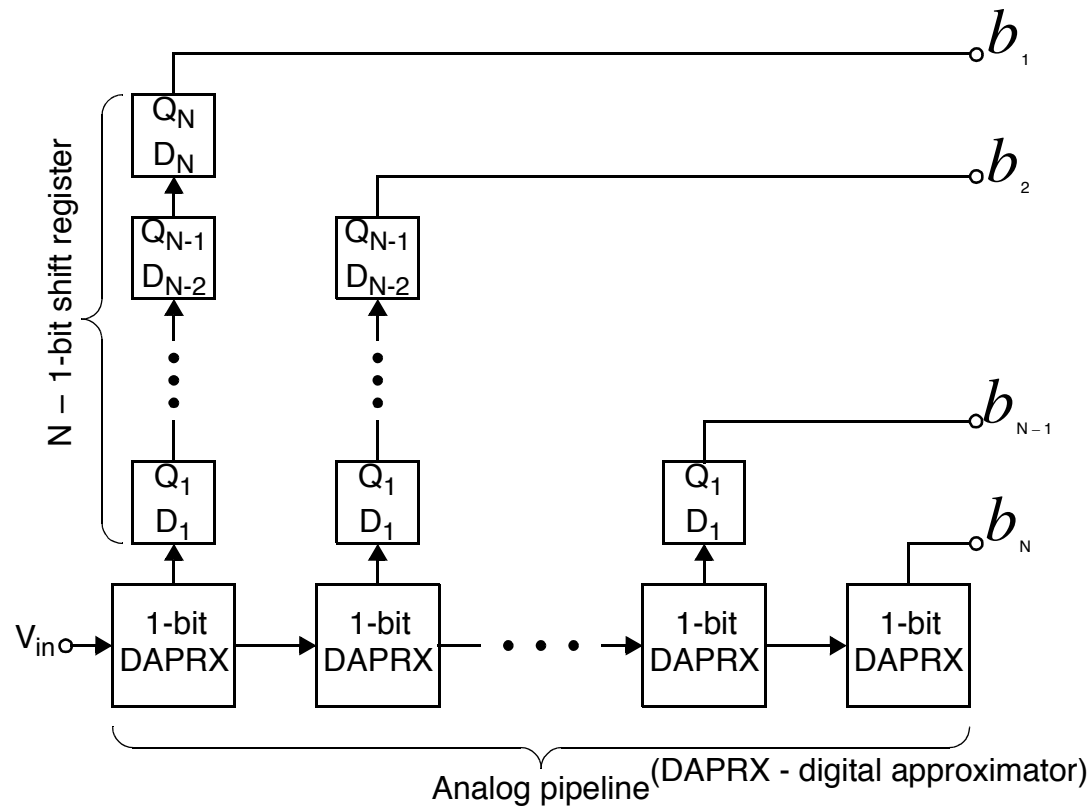
(b)

Folding with Interpolation

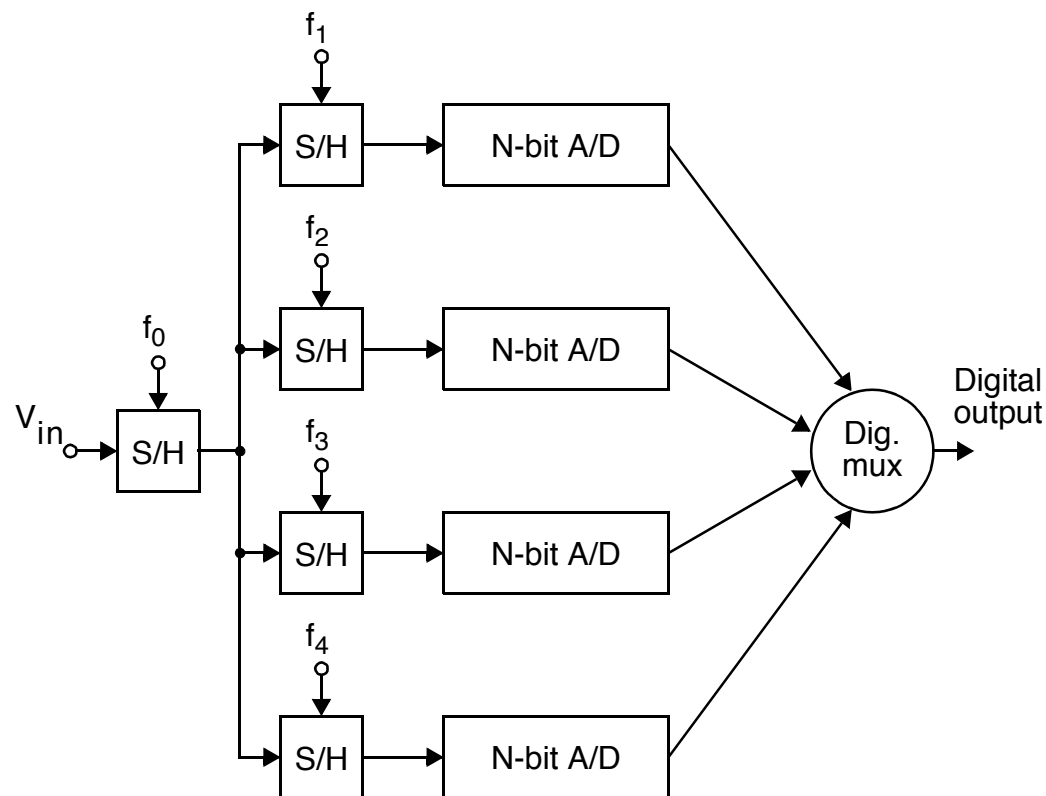


- Folding usually used with interpolation
- Reduces input cap (
- Without interp, same input cap as flash
- [van Valburg, 1992]
- [van de Grift, 1987]
- [Colleran, 1993]

Pipelined A/D Converters



Time-Interleaved A/D Converters [Black, 80]



- Use parallel A/Ds and multiplex them
- Tone occurs at f_s/N for N converters if mismatched
- Input S/H critical, others not — perhaps different tech for input S/H